

<b>Notice of References Cited</b>		Application/Control No.	Applicant(s)/Patent Under Reexamination CHEN ET AL.	
		Examiner Shantell Heiber	Art Unit 2617	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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*	B	US-2004/0165561	08-2004	Chiou et al.	370/338
*	C	US-6,535,745	03-2003	Seraj, Jila	455/458
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**NON-PATENT DOCUMENTS**

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